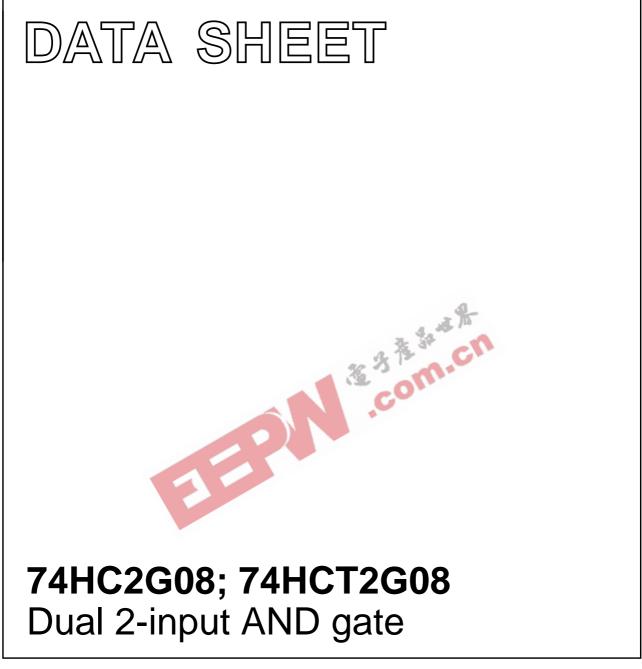
# INTEGRATED CIRCUITS



Product specification Supersedes data of 2003 Feb 03 2003 Oct 22



#### FEATURES

- Wide supply voltage range from 2.0 to 6.0  ${\rm V}$
- Symmetrical output impedance
- High noise immunity
- · Low power dissipation
- Balanced propagation delays
- Very small 8 pins package
- Output capability is standard
- ESD protection: HBM EIA/JESD22-A114-A exceeds 2000 V MM EIA/JESD22-A115-A exceeds 200 V.
- Specified from -40 to  $+85 \ ^\circ\text{C}$  and -40 to  $+125 \ ^\circ\text{C}$ .

#### QUICK REFERENCE DATA

GND = 0 V;  $T_{amb} = 25 \text{ °C}$ ;  $t_r = t_f \le 6.0 \text{ ns.}$ 

### 74HC2G08; 74HCT2G08

#### DESCRIPTION

The 74HC2G/HCT2G08 is a high-speed Si-gate CMOS device.

The 74HC2G/HCT2G08 provides the 2-input AND function.

£...

		2. 40	TYP		
SYMBOL	PARAMETER	CONDITIONS	HC2G08	HCT2G08	UNIT
t <sub>PHL</sub> /t <sub>PLH</sub>	propagation delay nA, nB to nY	C <sub>L</sub> = 15 pF; V <sub>CC</sub> = 5 V	9	14	ns
CI	input capacitance		1.5	1.5	pF
C <sub>PD</sub>	power dissipation capacitance per gate	notes 1 and 2	10	10	pF

#### Notes

1.  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu$ W).

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} \times N + \Sigma (C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$ 

f<sub>i</sub> = input frequency in MHz;

 $f_o = output frequency in MHz;$ 

 $C_L$  = output load capacitance in pF;

V<sub>CC</sub> = supply voltage in Volts;

N = total load switching outputs;

 $\Sigma (C_L \times V_{CC}^2 \times f_o) = sum of outputs.$ 

2. For 74HC2G08 the condition is  $V_I$  = GND to  $V_{CC}$ . For 74HCT2G08 the condition is  $V_I$  = GND to  $V_{CC}$  – 1.5 V.

# 74HC2G08; 74HCT2G08

**FUNCTION TABLE** 

See note 1.

INF	OUTPUT	
nA	nB	nY
L	L	L
L	Н	L
Н	L	L
Н	Н	Н

#### Note

1. H = HIGH voltage level;

L = LOW voltage level.

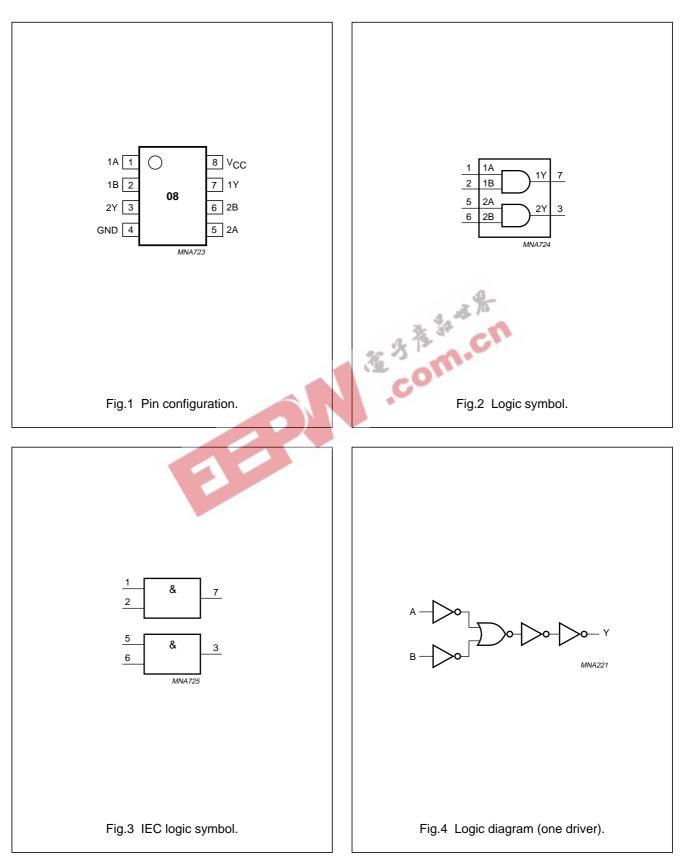
#### **ORDERING INFORMATION**

TYPE NUMBER	TEMPERATURE RANGE	PACKAGE					
	IEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE	MARKING	
74HC2G08DP	–40 to +125 °C	8	TSSOP8	plastic	SOT505-2	H08	
74HCT2G08DP	–40 to +125 °C	8	TSSOP8	plastic	SOT505-2	T08	
74HC2G08DC	–40 to +125 °C	8	VSSOP8	plastic	SOT765-1	H08	
74HCT2G08DC	-40 to +125 °C	8	VSSOP8	plastic	SOT765-1	T08	
PINNING							

#### PINNING

PIN	SYMBOL	DESCRIPTION
1	1A	data input
2	1B	data input
3	2Y	data output
4	GND	ground (0 V)
5	2A	data input
6	2B	data input
7	1Y	data output
8	V <sub>CC</sub>	supply voltage

### 74HC2G08; 74HCT2G08



### 74HC2G08; 74HCT2G08

#### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	CONDITIONS	7	4HC2G0	)8	74HCT2G08			
STMBOL		CONDITIONS	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
V <sub>CC</sub>	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	-	V <sub>CC</sub>	0	-	V <sub>CC</sub>	V
Vo	output voltage		0	-	V <sub>CC</sub>	0	-	V <sub>CC</sub>	V
T <sub>amb</sub>	operating ambient temperature	see DC and AC characteristics per device	-40	+25	+125	-40	+25	+125	°C
t <sub>r</sub> , t <sub>f</sub>	input rise and fall times	V <sub>CC</sub> = 2.0 V	-	-	1000	-	-	-	ns
		V <sub>CC</sub> = 4.5 V	-	6.0	500	-	6.0	500	ns
		$V_{CC} = 6.0 V$	-	-	400	-	-	-	ns

#### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage	30 3	-0.5	+7.0	V
I <sub>IK</sub>	input diode current	$V_{I} < -0.5 \text{ V or } V_{I} > V_{CC} + 0.5 \text{ V}; \text{ note 1}$	_	±20	mA
I <sub>ОК</sub>	output diode current	$V_{\rm O}$ < -0.5 V or $V_{\rm O}$ > $V_{\rm CC}$ + 0.5 V; note 1	_	±20	mA
I <sub>O</sub>	output source or sink current	–0.5 V < V <sub>O</sub> < V <sub>CC</sub> + 0.5 V; note 1	-	25	mA
I <sub>CC</sub> , I <sub>GND</sub>	V <sub>CC</sub> or GND current	note 1	_	50	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
PD	power dissipation	$T_{amb} = -40$ to +125 °C; note 2	_	300	mW

#### Notes

- 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 2. Above 110 °C the value of  $\mathsf{P}_\mathsf{D}$  derates linearly with 8 mW/K.

# 74HC2G08; 74HCT2G08

#### DC CHARACTERISTICS

#### Type 74HC2G08

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

OVMDO	DADAMETED	TEST CONDITIO	NS	RAINI	TYP.	MAX.	UNIT
SYMBOL	PARAMETER	OTHER	V <sub>cc</sub> (V)	MIN.	IIF.		
$T_{amb} = -40 tc$	<b>• +85</b> °C; note 1		-				
V <sub>IH</sub>	HIGH-level input voltage		2.0	1.5	1.2	_	V
			4.5	3.15	2.4	-	V
			6.0	4.2	3.2	-	V
V <sub>IL</sub>	LOW-level input voltage		2.0	-	0.8	0.5	V
			4.5	-	2.1	1.35	V
			6.0	-	2.8	1.8	V
V <sub>OH</sub>	HIGH-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$					
		I <sub>O</sub> = -20 μA	2.0	1.9 4.4	2.0	-	V
		I <sub>O</sub> = -20 μA	4.5	4.4	4.5	-	V
		I <sub>O</sub> = -20 μA	6.0	5.9	6.0	-	V
		$I_0 = -4.0 \text{ mA}$	4.5	4.13	4.32	-	V
		I <sub>O</sub> = -5.2 mA	6.0	5.63	5.81	-	V
V <sub>OL</sub>	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$					
		I <sub>O</sub> = 20 μA	2.0	-	0	0.1	V
		I <sub>O</sub> = 20 μA	4.5	-	0	0.1	V
		I <sub>O</sub> = 20 μA	6.0	-	0	0.1	V
		1 <sub>0</sub> = 4.0 mA	4.5	-	0.15	0.33	V
		l <sub>O</sub> = 5.2 mA	6.0	-	0.16	0.33	V
l <sub>LI</sub>	input leakage current	$V_I = V_{CC}$ or GND	6.0	-	-	±1.0	μA
I <sub>CC</sub>	quiescent supply current	$V_{I} = V_{CC}$ or GND; $I_{O} = 0$	6.0	-	-	10	μA

# 74HC2G08; 74HCT2G08

0/415.01		TEST CONDITION	IS			MAX.	
SYMBOL	PARAMETER	OTHER	V <sub>CC</sub> (V)	MIN.	TYP.		UNIT
$T_{amb} = -40 tc$	o +125 °C						
V <sub>IH</sub>	HIGH-level input voltage		2.0	1.5	-	-	V
			4.5	3.15	-	-	V
			6.0	4.2	-	_	V
V <sub>IL</sub>	LOW-level input voltage		2.0	-	-	0.5	V
			4.5	-	-	1.35	V
			6.0	-	-	1.8	V
V <sub>OH</sub>	HIGH-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$					
		I <sub>O</sub> = -20 μA	2.0	1.9	-	_	V
		I <sub>O</sub> = -20 μA	4.5	4.4	-	-	V
		I <sub>O</sub> = -20 μA	6.0	5.9	-	_	V
		I <sub>O</sub> = -4.0 mA	4.5	3.7	-	-	V
		I <sub>O</sub> = -5.2 mA	6.0	5.2	-	-	V
V <sub>OL</sub>	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$	1	C			
		Ι <sub>O</sub> = 20 μΑ	2.0	-	-	0.1	V
		I <sub>O</sub> = 20 μA	4.5	-	-	0.1	V
		l <sub>O</sub> = 20 μA	6.0	-	-	0.1	V
		I <sub>O</sub> = 4.0 mA	4.5	-	-	0.4	V
		$I_0 = 5.2 \text{ mA}$	6.0	-	-	0.4	V
ILI	input leakage current	$V_{I} = V_{CC}$ or GND	6.0	-	-	±1.0	μΑ
I <sub>CC</sub>	quiescent supply current	$V_1 = V_{CC}$ or GND; $I_0 = 0$	6.0	-	-	20	μA

#### Note

1. All typical values are measured at  $T_{amb} = 25 \text{ °C}$ .

# 74HC2G08; 74HCT2G08

#### Type 74HCT2G08

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CVMDOI		TEST CONDITIC	ONS		TVD		
SYMBOL	PARAMETER	OTHER	V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	
$T_{amb} = -40 \text{ to}$	• +85 °C; note 1						
V <sub>IH</sub>	HIGH-level input voltage		4.5 to 5.5	2.0	1.6	-	V
V <sub>IL</sub>	LOW-level input voltage		4.5 to 5.5	-	1.2	0.8	V
V <sub>OH</sub>	HIGH-level output voltage	$V_I = V_{IH} \text{ or } V_{IL}$ $I_O = -20 \ \mu\text{A}$ $I_O = -4.0 \ \text{mA}$	4.5 4.5	4.4	4.5 4.32	_	V V
V <sub>OL</sub>	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$ $I_{O} = 20 \ \mu\text{A}$ $I_{O} = 4.0 \text{ mA}$	4.5 4.5		0 0.15	0.1 0.33	V V
ILI	input leakage current	$V_{I} = V_{CC}$ or GND	5.5	- 4	-	±1.0	μA
I <sub>CC</sub>	quiescent supply current	$V_1 = V_{CC}$ or GND; $I_0 = 0$	5.5	14 In	-	10	μA
ΔI <sub>CC</sub>	additional supply current per input	$V_{\rm I} = V_{\rm CC} - 2.1 \text{ V}; I_{\rm O} = 0$	4.5 to 5.5	-	-	375	μA
$T_{amb} = -40 \text{ to}$	o +125 °C		CU				
V <sub>IH</sub>	HIGH-level input voltage		4.5 to 5.5	2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage		4.5 to 5.5	-	-	0.8	V
V <sub>OH</sub>	HIGH-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$ $I_{O} = -20 \ \mu\text{A}$ $I_{O} = -4.0 \ \text{mA}$	4.5 4.5	4.4 3.7			v v
V <sub>OL</sub>	LOW-level output voltage	$V_I = V_{IH} \text{ or } V_{IL}$ $I_O = 20 \ \mu\text{A}$ $I_O = 4.0 \ \text{mA}$	4.5 4.5			0.1 0.4	v v
I <sub>LI</sub>	input leakage current	$V_I = V_{CC}$ or GND	5.5	_	-	±1.0	μA
I <sub>CC</sub>	quiescent supply current	$V_{I} = V_{CC}$ or GND; $I_{O} = 0$	5.5	-	_	20	μA
$\Delta I_{CC}$	additional supply current per input	$V_{I} = V_{CC} - 2.1 \text{ V}; I_{O} = 0$	4.5 to 5.5	-	_	410	μA

#### Note

1. All typical values are measured at  $T_{amb}$  = 25 °C.

# 74HC2G08; 74HCT2G08

#### AC CHARACTERISTICS

#### Type 74HC2G08

 $GND = 0 \text{ V}; t_r = t_f \leq 6.0 \text{ ns}; C_L = 50 \text{ pF}.$ 

	PARAMETER	TEST CONDIT	IONS	NAINI	TYP.		
SYMBOL	PARAMETER	WAVEFORMS	V <sub>CC</sub> (V)	MIN.		MAX.	UNIT
$T_{amb} = -40$	to +85 °C; note 1	·					
t <sub>PHL</sub> /t <sub>PLH</sub>	propagation delay nA, nB to nY	see Figs 5 and 6	2.0	-	26	95	ns
			4.5	-	9	19	ns
			6.0	-	8	16	ns
t <sub>THL</sub> /t <sub>TLH</sub>	output transition time	see Figs 5 and 6	2.0	-	20	95	ns
			4.5	-	7	19	ns
			6.0	-	6	16	ns
T <sub>amb</sub> = -40	to +125 °C	-				•	
t <sub>PHL</sub> /t <sub>PLH</sub>	propagation delay nA, nB to nY	see Figs 5 and 6	2.0	z M	_	110	ns
			4.5	-	-	22	ns
		20 3	6.0	-01	-	20	ns
t <sub>THL</sub> /t <sub>TLH</sub>	output transition time	see Figs 5 and 6	2.0	<u>-</u>	_	125	ns
			4.5	-	_	25	ns
			6.0	-	_	20	ns

#### Note

1. All typical values are measured at  $T_{amb} = 25$  °C.

#### Type 74HCT2G08

GND = 0 V;  $t_r = t_f \le 6.0 \text{ ns}$ ;  $C_L = 50 \text{ pF}$ .

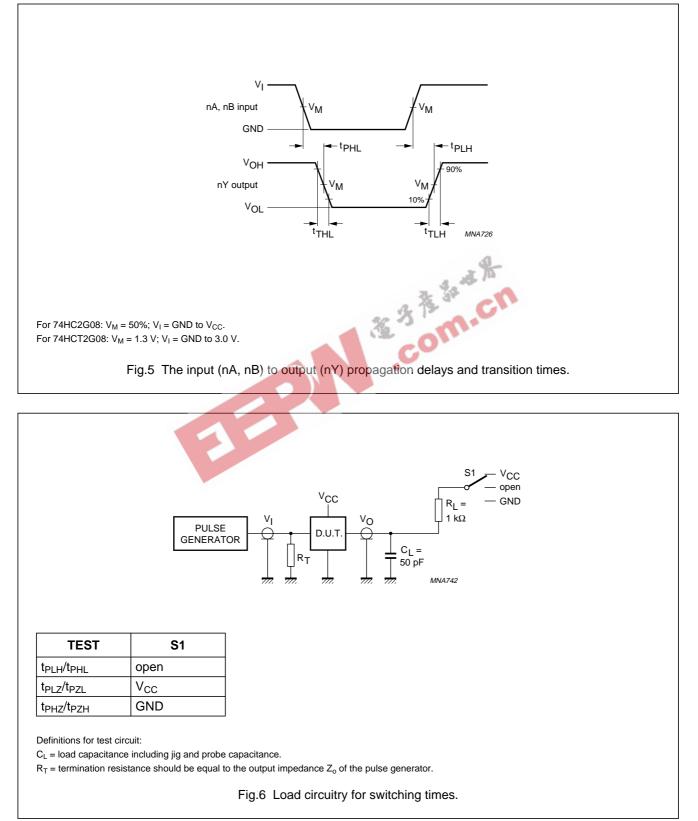
SYMBOL		PARAMETER TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
STNIDUL	PARAMETER	WAVEFORMS	V <sub>cc</sub> (V)	WIIIN.			UNIT
T <sub>amb</sub> = -40 t	<b>o +85</b> ° <b>C</b> ; note 1						
t <sub>PHL</sub> /t <sub>PLH</sub>	propagation delay nA, nB to nY	see Figs 5 and 6	4.5	-	14	30	ns
t <sub>THL</sub> /t <sub>TLH</sub>	output transition time	see Figs 5 and 6	4.5	_	7	19	ns
T <sub>amb</sub> = -40 t	o +125 °C						
t <sub>PHL</sub> /t <sub>PLH</sub>	propagation delay nA, nB to nY	see Figs 5 and 6	4.5	-	-	36	ns
t <sub>THL</sub> /t <sub>TLH</sub>	output transition time	see Figs 5 and 6	4.5	_	_	22	ns

#### Note

1. All typical values are measured at  $T_{amb} = 25 \ ^{\circ}C$ .

### 74HC2G08; 74HCT2G08

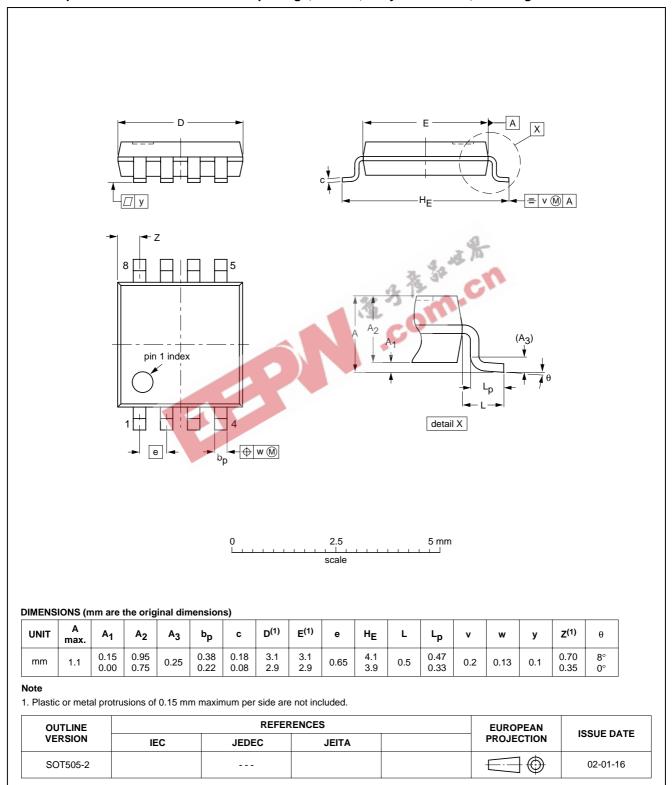
#### AC WAVEFORMS



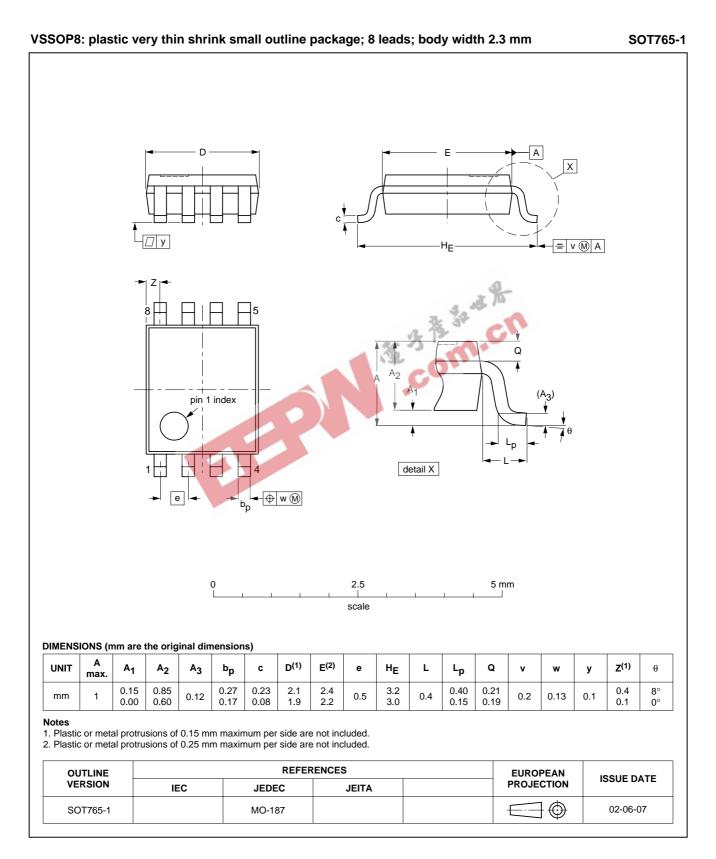
### 74HC2G08; 74HCT2G08

#### PACKAGE OUTLINES

TSSOP8: plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm SOT505-2



### 74HC2G08; 74HCT2G08



#### SOLDERING

#### Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering can still be used for certain surface mount ICs, but it is not suitable for fine pitch SMDs. In these situations reflow soldering is recommended.

#### **Reflow soldering**

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement. Driven by legislation and environmental forces the worldwide use of lead-free solder pastes is increasing.

Several methods exist for reflowing; for example, convection or convection/infrared heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 to 270 °C depending on solder paste material. The top-surface temperature of the packages should preferably be kept:

- below 220 °C (SnPb process) or below 245 °C (Pb-free process)
  - for all BGA and SSOP-T packages
  - for packages with a thickness  $\geq$  2.5 mm
  - − for packages with a thickness < 2.5 mm and a volume  $\ge$  350 mm<sup>3</sup> so called thick/large packages.
- below 235 °C (SnPb process) or below 260 °C (Pb-free process) for packages with a thickness < 2.5 mm and a volume < 350 mm<sup>3</sup> so called small/thin packages.

Moisture sensitivity precautions, as indicated on packing, must be respected at all times.

#### Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

### 74HC2G08; 74HCT2G08

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.
- For packages with leads on two sides and a pitch (e):
  - larger than or equal to 1.27 mm, the footprint longitudinal axis is **preferred** to be parallel to the transport direction of the printed-circuit board;
  - smaller than 1.27 mm, the footprint longitudinal axis must be parallel to the transport direction of the printed-circuit board.

The footprint must incorporate solder thieves at the downstream end.

• For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time of the leads in the wave ranges from 3 to 4 seconds at 250 °C or 265 °C, depending on solder material applied, SnPb or Pb-free respectively.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

#### Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320  $^\circ\text{C}.$ 

### 74HC2G08; 74HCT2G08

#### Suitability of surface mount IC packages for wave and reflow soldering methods

PACKAGE <sup>(1)</sup>	SOLDERING METHOD		
PACKAGE (***	WAVE	REFLOW <sup>(2)</sup>	
BGA, LBGA, LFBGA, SQFP, SSOP-T <sup>(3)</sup> , TFBGA, VFBGA	not suitable	suitable	
DHVQFN, HBCC, HBGA, HLQFP, HSQFP, HSOP, HTQFP, HTSSOP, HVQFN, HVSON, SMS	not suitable <sup>(4)</sup>	suitable	
PLCC <sup>(5)</sup> , SO, SOJ	suitable	suitable	
LQFP, QFP, TQFP	not recommended <sup>(5)(6)</sup>	suitable	
SSOP, TSSOP, VSO, VSSOP	not recommended <sup>(7)</sup>	suitable	

#### Notes

- 1. For more detailed information on the BGA packages refer to the "(*LF*)BGA Application Note" (AN01026); order a copy from your Philips Semiconductors sales office.
- 2. All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the "Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods".
- 3. These transparent plastic packages are extremely sensitive to reflow soldering conditions and must on no account be processed through more than one soldering cycle or subjected to infrared reflow soldering with peak temperature exceeding 217 °C ± 10 °C measured in the atmosphere of the reflow oven. The package body peak temperature must be kept as low as possible.
- 4. These packages are not suitable for wave soldering. On versions with the heatsink on the bottom side, the solder cannot penetrate between the printed-circuit board and the heatsink. On versions with the heatsink on the top side, the solder might be deposited on the heatsink surface.
- 5. If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.
- 6. Wave soldering is suitable for LQFP, TQFP and QFP packages with a pitch (e) larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.
- 7. Wave soldering is suitable for SSOP, TSSOP, VSO and VSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.

### 74HC2G08; 74HCT2G08

#### DATA SHEET STATUS

LEVEL	DATA SHEET STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)(3)</sup>	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).
Notes			3 15 15

#### Notes

- 1. Please consult the most recently issued data sheet before initiating or completing a design.
- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status. 3

#### DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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